

<b>Notice of References Cited</b>	Application/Control No. 10/626,840	Applicant(s)/Patent Under Reexamination VAN DE BEEK ET AL.	
	Examiner YOUNG T. TSE	Art Unit 2611	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,421,379 B1	07-2002	Vannatta et al.	375/229
*	B	US-7,046,738 B1	05-2006	Dent, Paul W.	375/296
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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